

<b>Notice of References Cited</b>	Application/Control No. 10/784,495	Applicant(s)/Patent Under Reexamination CHEVALLIER, CHRISTOPHE	
	Examiner Viet Q Nguyen	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,477,107	11-2002	Lee, Jung-bae	365/233
	B	US-6,795,326	09-2004	Chevallier, Christophe	365/63
	C	US-6,542,406	04-2003	Byeon et al.	365/185.13
	D	US-6,151,271	11-2000	Lee, Jung-bae	365/233
	E	US-5,446,698	08-1995	McClure, David C.	365/230.03
	F	US-6,240,007	05-2001	Kang, Hee Bok	365/145
	G	US-6,507,515	01-2003	Taniguchi, Tsutomu	365/185.17
	H	US-6,064,592	05-2000	Nakagawa et al.	365/185.05
	I	US-6,282,145	08-2001	Tran et al.	365/230.06
	J	US-2003/0090949	05-2003	Tedrow et al.	365/200
	K	US-2004/0022092	02-2004	Dvir et al.	365/200
	L	US-			
	M	US-			

**VIET Q. NGUYEN  
PRIMARY EXAMINER**

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.